

**DETAILED ACTION**

**EXAMINER'S AMENDMENT**

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows:

- a. On page 2 of the Specification on line 29 delete "having the characteristics defined in claims 4 to 9";
- b. On page 3 of the specification on line 6 delete "in claims 10-13";
- c. On page 3 of the Specification on line 17 delete "this method having the characteristics defined in claim 14";
- d. On page 3 of the Specification on line 22 delete "this method having the characteristics defined in claim 15".

***Priority***

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

***Allowable Subject Matter***

2. Claims 16-19 are allowed over the prior art of record.
3. The following is an examiner's statement of reasons for allowance:

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Regarding claim 16, the prior art fails to disclose or make obvious an apparatus for determining the internal outline of a duct or cavity having conoscope means interposed between the receiving reflector means and the detection means and suitable for producing, with the light guided by the reflector means, a holographic image with concentric interference fringes which is detectable by the detection means, the periods of the fringes being correlated with the optical distance of the illuminated point, and in combination with the other recited limitations of claim 16.

Regarding claim 17, the prior art fails to disclose or make obvious a probe for an apparatus for determining the internal outline of a duct or cavity having the micro-mirror element is rotatably articulated to the probe arm element so as to be orientable in a radial plane relative to the probe arm element, wherein the micro-mirror element is integral to one end of a lever element articulated to the distal end of the probe arm element, the free end of the lever element being operable by a control rod element which is arranged parallel to the probe arm element and can translate along its longitudinal axis, and in combination with the other recited limitations of claim 17.

Regarding claim 18, the prior art fails to disclose or make obvious a probe for an apparatus for determining the internal outline of a duct or cavity having the micro-mirror element is rotatably articulated to the probe arm element so as to be orientable in a radial plane relative to the probe arm element, wherein an electrical current can flow through the micro-mirror element which is disposed between a pair of elongate conductor elements suitable for bringing about rotation of the micro-mirror as a result of the electrical currents passing through them, and in combination with the other recited limitations of claim 18.

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Regarding claim 19, the prior art fails to disclose or make obvious a probe for an apparatus for determining the internal outline of a duct or cavity having the micro-mirror element is rotatably articulated to the probe arm element so as to be orientable in a radial plane relative to the probe arm element, wherein the probe arm element is made of ferromagnetic material and is wound up, along its length, by a winding capable of conducting current, the micro-mirror element also being made of ferromagnetic material, so that the rotation of the micro-mirror is brought about by a magnetic field produced by the current passing through the winding, and in combination with the other recited limitations of claim 19.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to /Michael P. Stafira/ whose telephone number is 571-272-2430. The examiner can normally be reached on 4/10 Schedule Mon.-Thurs..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Tarifur Chowdhury can be reached on 571-272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Michael P. Stafira/  
Primary Examiner  
Art Unit 2886

April 17, 2009